

Search Notes

Application/Control No.

10/652,787

Examiner

Chau Nguyen

Applicant(s)/Patent under
Reexamination

LAYZELL ET AL.

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	517	2/23/2006	CN
715	518	2/23/2006	CN
715	519	2/23/2006	CN
715	503	2/23/2006	CN
715	508	2/23/2006	CN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Reports	02/23/2006	CN
	2/24/2006	CN
NPL Search on IEEE Database	3/1/2006	CN